

(19) World Intellectual Property
Organization
International Bureau



(43) International Publication Date
18 August 2005 (18.08.2005)

PCT

(10) International Publication Number
WO 2005/075971 A1

(51) International Patent Classification⁷: G01N 27/447,
B01L 3/00

(21) International Application Number:
PCT/EP2004/050069

(22) International Filing Date: 2 February 2004 (02.02.2004)

(25) Filing Language: English

(26) Publication Language: English

(71) Applicant (for all designated States except US): AGI-
LENT TECHNOLOGIES INC. [US/US]; 395 Page Mill
Road, Palo Alto, California 94306 (US).

(72) Inventor; and

(75) Inventor/Applicant (for US only): LÜDKE, Gerd
[DE/DE]; Wilhelmstr. 17, 71088 Holzgerlingen (DE).

(74) Agent: BARTH, Daniel; Herrenberger Str. 130, 71034
Böblingen (DE).

(81) Designated States (unless otherwise indicated, for every
kind of national protection available): AE, AG, AL, AM,

AT, AU, AZ, BA, BB, BG, BR, BW, BY, BZ, CA, CH, CN,
CO, CR, CU, CZ, DE, DK, DM, DZ, EC, EE, EG, ES, FI,
GB, GD, GE, GH, GM, HR, HU, ID, IL, IN, IS, JP, KE,
KG, KP, KR, KZ, LC, LK, LR, LS, LT, LU, LV, MA, MD,
MG, MK, MN, MW, MX, MZ, NA, NI, NO, NZ, OM, PG,
PH, PL, PT, RO, RU, SC, SD, SE, SG, SK, SL, SY, TJ, TM,
TN, TR, TT, TZ, UA, UG, US, UZ, VC, VN, YU, ZA, ZM,
ZW.

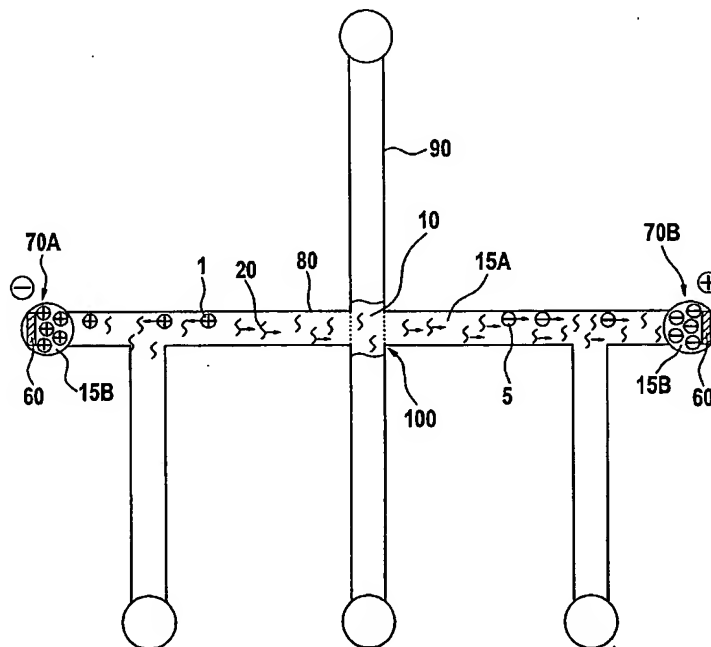
(84) Designated States (unless otherwise indicated, for every
kind of regional protection available): ARIPO (BW, GH,
GM, KE, LS, MW, MZ, SD, SL, SZ, TZ, UG, ZM, ZW),
Eurasian (AM, AZ, BY, KG, KZ, MD, RU, TJ, TM), Euro-
pean (AT, BE, BG, CH, CY, CZ, DE, DK, EE, ES, FI, FR,
GB, GR, HU, IE, IT, LU, MC, NL, PT, RO, SE, SI, SK,
TR), OAPI (BF, BJ, CF, CG, CI, CM, GA, GN, GQ, GW,
ML, MR, NE, SN, TD, TG).

Published:

— with international search report

For two-letter codes and other abbreviations, refer to the "Guid-
ance Notes on Codes and Abbreviations" appearing at the begin-
ning of each regular issue of the PCT Gazette.

(54) Title: CHARGED PARTICLE REDUCTION IN ANALYTE PROCESSING



(57) Abstract: The invention discloses a method for processing analytes (20) in a first solution (15A) also containing charged parti-
cles (1, 5), the first solution being in a compartment, comprising the method steps of subjecting said compartment to an electric field,
thereby reducing the amount of the charged particles (1, 5) in a part (10) of the first solution 15A, which is located in a section of the
compartment, and subjecting said part (10) of the first solution obtained in step A) containing the analytes (20) to further processing.

WO 2005/075971 A1